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Toward Atomic Resolution Z-Contrast Electron Tomography

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Z-contrast imaging can usually produces scanning a focus beam with diameter close to the atomic spacing across the sample. Only the high angle diffractive beams are collected and form the Z-contrast images. However, the focus beam can be easily damage the sample, especially for the beam sensitive materials. In our talk, we will discuss our dream and the up to date progress in the electron diffractive tomography and atomic resolution z-contrast electron tomography.

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